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other sensing devices.

Write a short note on AC electric measurements.

18NT53

(08 Marks)

(04 Marks)

Fifth Semester B.E. Degree Examination, July/August 2021 **Characterization Techniques**

Time: 3 hrs.

lax. Marks: 100

1 111	ie. 3	Note: Answer any FIVE full questions.	
		Explain in detail about Rayleigh criterion and Abbe criterion.	(08 Marks)
1	a.	Mention the different compositional characterization tools and explain any two br	iefly.
	b.	Mendon the different compositional characterisation	(12 Marks)
2	a.	Explain the electron diffraction and interference with suitable diagram.	(08 Marks)
	b.	Mention the different structural characterization tools. Explain any two in detail.	(12 Marks)
3	a.	Explain the working of XPS along with a neat schematic.	(08 Marks)
3	b.	Explain the basic principle of powder XRD. Mention the advantages and disadvar	ntages.
	U.	J (→Y	(no Marks)
	c.	Mention the applications of powder XRD and write an equation to find of	ut average
		thickness of a given sample.	(04 Marks)
4	a.	With a schematic, explain the working of single crystalline XRD.	(08 Marks)
•	b.	Explain the basic principle of single crystalline XRD. Mention the adva	ntages and
	o.	limitations.	(08 Marks)
	c.	Write a short note on XANES.	(04 Marks)
-		With a neat schematic, explain the working of SEM.	(08 Marks)
5	a.	Briefly explain the working of STM with a neat schematic.	(08 Marks)
	b.	Write a short note on electron beam interaction with matter.	(04 Marks)
	c.		(00.35 1.)
6	a.	With a neat schematic diagram, explain the working of TEM.	(08 Marks)
	b.	Explain the basic principle of SEM. Mention the advantages and limitations.	(08 Marks)
	c.	Write a short note on selective area electron diffraction.	(04 Marks)
_		With a scheme, explain the working of UV-Vis spectrometer.	(08 Marks)
7	a.	Define zeta potential. Explain the process of measuring zeta potential and its app	lications.
	b.	Denne zeta potentiai. Explant the process of measuring 11	(08 Marks)
	_	Mention the advantages and limitations of FTIR.	(04 Marks)
	7		
8	a.	Explain the working of Raman spectroscopy with a schematic.	(08 Marks)
	Ъ.	Explain dynamic light scattering method along with neat schematic for nano	particle size
		measurement.	(US Marks)
	c.	Mention the advantages and limitations of Raman spectroscopy.	(04 Marks)
		Define Potentiometry. Explain the working principle of potentiometry with a near	at schematic.
9	a.		(UO IVIAIRS)
	L	Explain impedance measurement and analysis using LCR meter with a schemati	c. (08 Marks)
	b.	TV 1 1 1 DC -1-atria maggirement	(04 Marks)
	c.		
10) a.	Explain the working process of linear sweep voltametry.	(08 Marks)
10		The last is complified method to measure AC signals for low power nanoted	chnology and

b. Explain lock in amplifier method to measure AC signals for low power nanotechnology and

2. Any revealing of identification, appeal to evaluator and /or equations written eg, 42+8 = 50, will be treated as malpractice. Important Note: 1. On completing your answers, compulsorily draw diagonal cross lines on the remaining blank pages.